

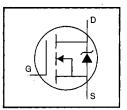
EN: This Datasheet is presented by the manufacturer.

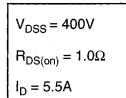
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# International Rectifier

## HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements

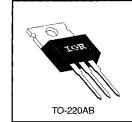




## Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10 V	5.5	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, VGS @ 10 V	3.5	Α
I <sub>DM</sub>	Pulsed Drain Current ①	22	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	74	W
	Linear Derating Factor	0.59	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
Eas	Single Pulse Avalanche Energy ②	290	mJ
lan	Avalanche Current ①	5.5	Α
EAR	Repetitive Avalanche Energy ①	7.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns
TJ	Operating Junction and	-55 to +150	
Tstg	Storage Temperature Range		.c
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

#### Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Reuc	Junction-to-Case			1.7	
Recs	Case-to-Sink, Flat, Greased Surface	_	0.50		°C/W
Reja	Junction-to-Ambient	_	_	62	1



# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	400	_	_	V	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA	
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	_	0.54	_	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA	
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		_	1.0	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =3.3A ④	
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	_	4.0	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA	
g <sub>fs</sub>	Forward Transconductance	2.9		_	S	V <sub>DS</sub> =50V, I <sub>D</sub> =3.3A ⊕	
	Darie to Comment	_	_	25	μА	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V	
loss	Drain-to-Source Leakage Current	_	_	250		V <sub>DS</sub> =320V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C	
less	Gate-to-Source Forward Leakage	_	_	100	nA	V <sub>GS</sub> =20V	
IGSS	Gate-to-Source Reverse Leakage	_		-100	''A	V <sub>GS</sub> =-20V	
Qg	Total Gate Charge			38		I <sub>D</sub> =3.5A	
Qgs	Gate-to-Source Charge		. —	5.7	nC	V <sub>DS</sub> =320V	
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			22		V <sub>GS</sub> =10V See Fig. 6 and 13 ④	
td(on)	Turn-On Delay Time		10	_		V <sub>DD</sub> =200V	
t <sub>r</sub>	Rise Time	_	15	_	ns	I <sub>D</sub> =3.5A	
t <sub>d(off)</sub>	Turn-Off Delay Time	_	38	_	113	R <sub>G</sub> =12Ω	
tr	Fall Time	_	14	_		R <sub>D</sub> =57Ω Seé Figure 10	
LD	Internal Drain Inductance	_	4.5	_	nН	Between lead, 6 mm (0.25in.)	
Ls	Internal Source Inductance	_	7.5		11171	from package and center of die contact	
Ciss	Input Capacitance	_	700	_		V <sub>GS</sub> =0V	
Coss	Output Capacitance		170		pF	V <sub>DS</sub> =25V	
Crss	Reverse Transfer Capacitance	_	64			f=1.0MHz See Figure 5	

# Source-Drain Ratings and Characteristics

	<u> </u>						
	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
ls	Continuous Source Current (Body Diode)	_	_	5.5	A	MOSFET symbol showing the	
Ism	Pulsed Source Current (Body Diode) ①	_	_	22		integral reverse p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage		_	1.6	٧	T <sub>J</sub> =25°C, I <sub>S</sub> =5.5A, V <sub>GS</sub> =0V @	
t <sub>rr</sub>	Reverse Recovery Time	_	270	530	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =3.5A	
Q <sub>rr</sub>	Reverse Recovery Charge		1.8	2.2	μC	di/dt⊨100A/μs ④	
ton	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+LD)				

#### Notes:

- Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③ I<sub>SD</sub>≤5.5A, di/dt≤90A/ $\mu$ s, V<sub>DD</sub>≤V(BR)Dss, T<sub>J</sub>≤150°C
- ⓐ Pulse width ≤ 300  $\mu$ s; duty cycle ≤2%.

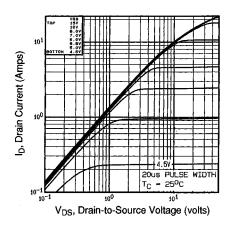


Fig 1. Typical Output Characteristics, T<sub>C</sub>=25°C

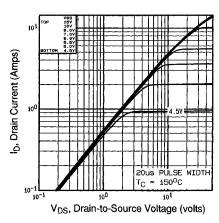


Fig 2. Typical Output Characteristics, T<sub>C</sub>=150°C

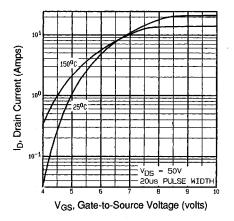


Fig 3. Typical Transfer Characteristics

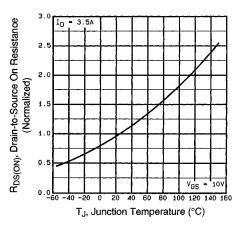


Fig 4. Normalized On-Resistance Vs. Temperature

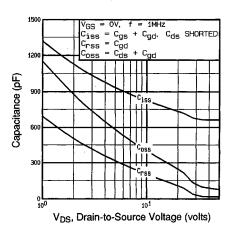


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

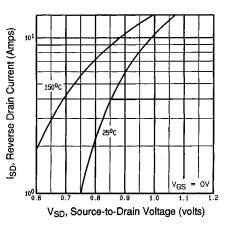


Fig 7. Typical Source-Drain Diode Forward Voltage

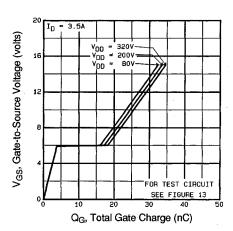


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

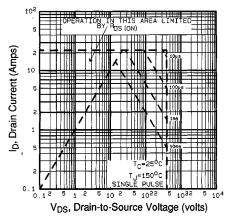


Fig 8. Maximum Safe Operating Area

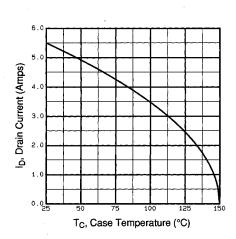


Fig 9. Maximum Drain Current Vs. Case Temperature

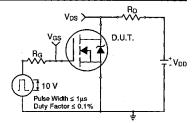


Fig 10a. Switching Time Test Circuit

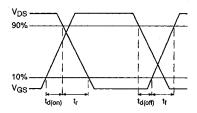


Fig 10b. Switching Time Waveforms

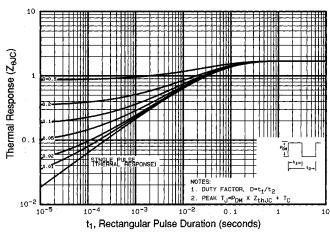


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

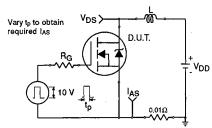


Fig 12a. Unclamped Inductive Test Circuit

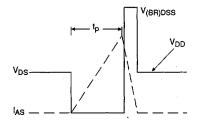


Fig 12b. Unclamped Inductive Waveforms

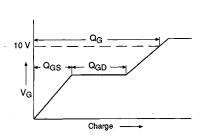


Fig 13a. Basic Gate Charge Waveform

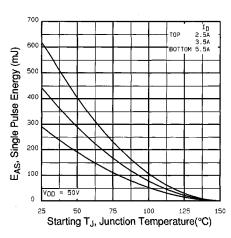


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

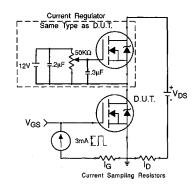


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit - See page 1505

Appendix B: Package Outline Mechanical Drawing - See page 1509

Appendix C: Part Marking Information – See page 1516

Appendix E: Optional Leadforms – See page 1525

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